1. Record Nr.   UNINA9910872769203321

Titolo	2000 IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems
Pubbl/distr/stampa	[Place of publication not identified], : IEEE Computer Society Press, 2000
Descrizione fisica	1 online resource (438 pages)
Disciplina	004.2
Soggetti	Fault-tolerant computing
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph
Sommario/riassunto	This volume includes 45 papers presented at the October 2000 symposium, covering yield analysis, modeling, and enhancement; fault tolerance interconnections and systems; reconfiguration and repair; error coding; online testing; testing and BIST techniques; and fault injection techniques and environments. The authors, professionals and academics from 18 different companies, offer papers on specific topics such as quality-effective repair of multichip module systems, evaluations of burst error recovery for VF arithmetic coding, and test cost minimization for Hybrid BIST. A thorough subject index is lacking. Annotation copyrighted by Book News, Inc., Portland, OR.